

## $2^{nd}$ generation thinQ!<sup>TM</sup> SiC Schottky Diode

#### Features:

#### **Applications:**

SMPS, PFC, snubber

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- Revolutionary Semiconductor Material -Silicon Carbide
- Switching Behaviour Benchmark
- No Reverse Recovery / No Forward Recovery
- Temperature Independent Switching Behaviour
- Qualified According to JEDEC<sup>1)</sup> Based on Target Applications

Chip Type	$V_{R}$	<i>I</i> <sub>Fn</sub>	Die Size	Package
IDC04S60CE	600V	4A	1.146 x 0.968 mm <sup>2</sup>	sawn on foil

Mechanical Parameter	'S	1		
Die size		1.146x 0.968		
Area total		1.11		
Anode pad size		0.909 x 0.731		
Thickness		355	μm	
Wafer size		100	mm	
Max. possible chips per	wafer	6190		
Passivation frontside		Photoimide		
Pad metal		3200 nm AlSiCu		
Backside metal		Ni Ag -system		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, ≤500μm		
Reject ink dot size		Ø 0.65mm; max 1.2mm		
1)	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25°C, < 6 month		
Storage environment <sup>1)</sup>	for open MBB bags	Acc. to IEC60721-3-3: Atmosphere >99% Nitrogen or in gas, Humidity <25%RH, Temperature 17°C – 25°C, < 6 m		

<sup>&</sup>lt;sup>1)</sup> Designed for storage conditions according to Infineon TR14 (Application Note "Storage of Products Supplied by Infineon Technologies)

Designed for climate condition under operation according to IEC60721-3-3, class 3K3



#### **Maximum Ratings**

Parameter	Symbol	Condition	Value	Unit
Repetitive peak reverse voltage	$V_{RRM}$	<i>T</i> <sub>vj</sub> =25 °C	600	V
DC blocking voltage	$V_{DC}$		600	7 V
Continuous forward current, limited by $T_{vjmax}$	I <sub>F</sub>	T <sub>vj</sub> < 150°C	4	
Surge non repetitive forward current,	,	$T_{\rm C}$ =25°C, $t_{\rm P}$ =10 ms	32	
sine halfwave	I <sub>F,SM</sub>	$T_{\rm C} = 150^{\circ} {\rm C}$ , $t_{\rm P} = 10 {\rm ms}$		A
Repetitive peak forward current, limited by thermal resistance $R_{th}$	I <sub>F,RM</sub>	$T_{\rm C} = 100^{\circ} {\rm C}, \ T_{\rm vj} = 150^{\circ} {\rm C},$ D = 0.1	18	
Non-repetitive peak forward current	$I_{F,max}$	$T_{\rm C} = 25^{\circ}{\rm C}, \ t_{\rm P} = 10 \mu{\rm s}$	132	
i <sup>2</sup> t value	$\int i^2 dt$	$T_{\rm C} = 25^{\circ}{\rm C}$ , $t_{\rm P} = 10 {\rm ms}$	5.1	- A <sup>2</sup> s
i t value	Ji ai	$T_{\rm C} = 150^{\circ} {\rm C}$ , $t_{\rm P} = 10 {\rm ms}$	ns	
Operating junction and storage temperature range	$T_{\rm vj}$ , $T_{\rm stg}$		-55+175	°C

### Static Characteristics (tested on wafer), $T_{vj}$ = 25 °C

Parameter	Symbol	Conditions	Value			Unit
Parameter		Conditions	min.	Тур.	max.	Oiiit
Reverse current	$I_{R}$	V <sub>R</sub> =600V		0.5	50	μA
Diode forward voltage	V <sub>F</sub>	I <sub>F</sub> =4A		1.7	1.9	V

#### Static Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions	Value			Unit
raiailletei	Syllibol	Conditions	min.	Тур.	max.	Oiiit
Reverse current	$I_{R}$	$V_{R} = 600 \text{V}, T_{vj} = 150 ^{\circ}\text{C}$		2	500	μA
Diode forward voltage	$V_{F}$	I <sub>F</sub> =4A, T <sub>vj</sub> =150°C		2	2.4	V



#### Dynamic Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol Condi		ons	Value			Unit
	Symbol	Conditi	Conditions		Тур.	max.	Onit
Total capacitive charge <sup>3)</sup>	Q <sub>C</sub>	$I_F <= I_{F,max}$	T <sub>vj</sub> =150°C		8		nC
Switching time <sup>2)</sup>	tc	di/dt=200A/μs V <sub>R</sub> =400V	T <sub>vj</sub> =150°C			<10	ns
			V <sub>R</sub> =1 V		130		
Total capacitance	С	f=1MHz	V <sub>R</sub> =300V		20		pF
			V <sub>R</sub> =600V		20		

#### **Further Electrical Characteristics**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

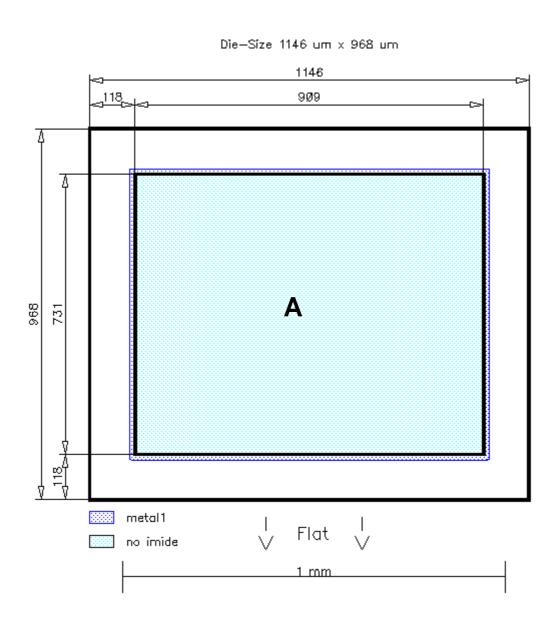
This chip data sheet refers to the device data sheet	IDT04S60C	Rev. 2.1
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 $<sup>^{1)}</sup>$  J-STD20 and JESD22  $^{2)}$   $t_{\rm c}$  is the time constant for the capacitive displacement current waveform (independent from  $T_{\rm vj}{=}150\,^{\circ}{\rm C}$ ,  $I_{\rm LOAD}$  and dl/dt), different from  $t_{\rm rr}$ , which is dependent on  $T_{\rm vj}$  =150°C,  $I_{\rm LOAD}$ , dl/dt. No reverse recovery time constant  $t_{\rm rr}$  due to absence of minority carrier inject.  $^{3)}$  Only capacitive charge occurring, guaranteed by design (independent from  $T_{\rm vj}$ ,  $I_{\rm LOAD}$  and dl/dt).





#### **Chip Drawing**



A: Anode pad



Description
AQL 0,65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

#### **Revision History**

Version	Subjects (major changes since last revision)	Date

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